

<b>Notice of References Cited</b>	Application/Control No. 10/816,584		Applicant(s)/Patent Under Reexamination NAM, NICHOLAS	
	Examiner TAN TRINH		Art Unit 2618	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0050059	03-2003	Tsukamoto, Tadashi	455/426
*	B	US-2004/0046783	03-2004	Montebovi, Franco	345/730
*	C	US-2006/0194619	08-2006	Wilcox et al.	455/566
*	D	US-6,795,715	09-2004	Kubo et al.	455/556.1
*	E	US-2004/0198437	10-2004	Yamamoto et al.	455/556.1
*	F	US-2003/0128197	07-2003	Turner et al.	345/204
*	G	US-2002/0055369	05-2002	Nakamura et al.	455/556
*	H	US-6,287,200	09-2001	Sharma, Dipanshu	463/40
*	I	US-6,871,243	03-2005	Iwase et al.	710/62
*	J	US-2003/0135748	07-2003	Yamada et al.	713/193
*	K	US-2002/0082043	06-2002	Wilska et al.	455/550
*	L	US-2005/0251694	11-2005	Ueda et al.	713/193
*	M	US-2003/0210461	11-2003	Ashizaki et al.	359/443

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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